

规格书编号

SPEC NO:

产品规格书 SPECIFICATION

CUSTOMER 客 户:			
PRODUCT 产品:	SAW FILTER		
MODEL NO 型 号:	HDBF09024C64 SF6-4		
PREPARED 编 制:	CHECKED 审 核:		
APPROVED 批准:	DATE 月期: 2008-12-18		
客户确认 CUSTOMER RI	ECEIVED:		
审核 CHECKED	批准 APPROVED	日期 DATE	

无锡市好达电子有限公司 Shoulder Electronics Limited



更改历史记录 History Record

更改日期 Date	规格书编号 Spec. No.	产品型号 Part No.	客户产品型号 Customer No.	更改内容描述 Modify Content	备注 Remark



1. SCOPE

This specification shall cover the characteristics of SAW filter HD BF09024C64

2. ELECTRICAL SPECIFICATION

Operation temperature	-40°C to +85°C
Storage temperature	-40°C to +105°C
DC Voltage VDC	0V
Input Power	10dBm Max

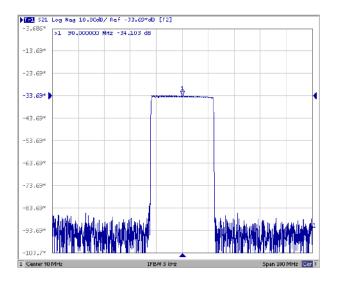
2.2 Electronic Characteristics

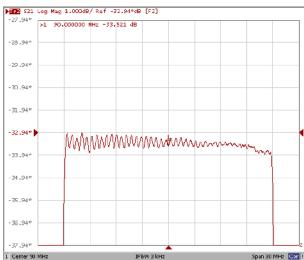
			Minimum	Typical	Maximum
Center Frequency		MHz	89.875	90	90.125
Insertion Loss	Insertion Loss		-	34	38
2dB Bandwidth		MHz	24	24.01	-
3dB Bandwidth		MHz		24.1	
40dB Bandwidth		MHz		24.8	
Passband variation		dB	-	0.9	
Absolute delay		us	-	3.93	4
	$F0 \pm 12.4 MHz$	dB	25	28	-
I Iltimata miaatian	$F0 \pm 12.6 MHz$	dB	40	53	
Ultimate rejection	$F0 \pm 13.0 MHz$	dB	50	53	
	$F0 \pm 17.0 MHz$	dB	50	53	
Material Temperature coefficient		KHz/°C		-8.46	
Ambient temperature		$^{\circ}$ C		25	



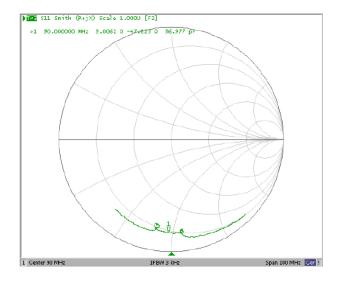
SAW FILTER

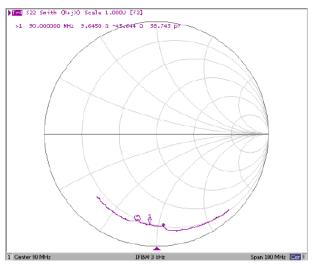
Typical frequency response





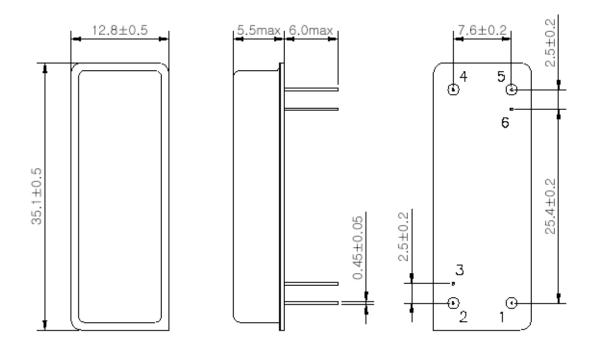
Smith Chart





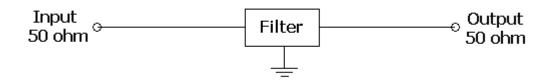


3. DIMENSION



Pin Configuration	
1	Input
5	Output
2, 4	Ground
Other	Case ground

4.TEST CIRCUIT



SAW FILTER

5. ENVIRONMENTAL CHARACTERISTICS

5-1 High temperature exposure

Subject the device to $+85^{\circ}$ C for 16 hours. Then release the filter into the room conditions for 24 hours prior to the measurement. It shall fulfill the specifications in 2.2.

5-2 Low temperature exposure

Subject the device to -40° C for 16 hours. Then release the device into the room conditions for 24 hours prior to the measurement. It shall fulfill the specifications in 2.2.

5-3 Temperature cycling

Subject the device to a low temperature of -40° C for 30 minutes. Following by a high temperature of $+85^{\circ}$ C for 30 Minutes. Then release the device into the room conditions for 24 hours prior to the measurement. It shall meet the specifications in 2.2.

5-4 Resistance to solder heat

Dip the device terminals no closer than 1.5mm into the solder bath at 260° C $\pm 10^{\circ}$ C for 10 ± 1 sec. Then release the device into the room conditions for 4 hours. The device shall meet the specifications in 2.2.

5-5 Solderability

Subject the device terminals into the solder bath at 245° C $\pm 5^{\circ}$ C for 5s, More than 95% area of the terminals must be covered with new solder. It shall meet the specifications in 2.2.

5-6 Mechanical shock

Drop the device randomly onto the concrete floor from the height of 1m 3 times. the device shall fulfill the specifications in 2.2.

5-7 Vibration

Subject the device to the vibration for 1 hour each in x,y and z axes with the amplitude of 1.5 mm at 10 to 55 Hz. The device shall fulfill the specifications in 2.2.

6. REMARK

6.1 Static voltage

Static voltage between signal load & ground may cause deterioration &destruction of the component. Please avoid static voltage.

6.2 Ultrasonic cleaning

Ultrasonic vibration may cause deterioration & destruction of the component. Please avoid ultrasonic cleaning

6.3 Soldering

Only leads of component may be soldered. Please avoid soldering another part of component.